

VERIFICATION OF COMPLIANCE

Equipment Under Test:

Panel PC (IPC)

Trade Name:

N/A

Model Number:

G3000

Serial Number:

N/A

EUT Powered during test: 230VAC/50Hz

Applicant:

AASIC Computer Inc.

4F-1, No. 131, Lane 235, Pao Chiao Rd., Hsin Tien,

Taipei Shian, Taiwan, R.O.C.

Manufacturer:

AASIC Computer Inc.

4F-1, No. 131, Lane 235, Pao Chiao Rd., Hsin Tien,

Taipei Shian, Taiwan, R.O.C.

Type of Test:

EMC Directive 89/336/EEC for CE Marking

Technical Standards:

EN 55022: 1994 + A1: 1995 + A2: 1997 (Class A)

EN 60555-2: 1987, EN 61000-3-3: 1995

EN 50082-2: 1995 (EN 61000-4-2: 1995, ENV 50140: 1994,

ENV 50141: 1994, EN 61000-4-4: 1995,

ENV 50204: 1996)

File Number:

000560-E

Date of test:

August 3 ~ 9, 2000

Deviation:

1. According to applicant's declaration this EUT is a class A product, and

to be market in industrial environment only.

The Class A limits of EN 61000-3-2 was used to instead of EN 60555-2

limits.

Condition of Test Sample: Normal

The above equipment was tested by C&C Laboratory Co., Ltd. for compliance with the requirements set forth in EMC Directive 89/336/EEC and the Technical Standards mentioned above. This said equipment in the configuration described in this report shows the maximum emission levels emanating from equipment and the level of the immunity endurance of the equipment are within the compliance requirements.

The test results of this report relate only to the tested sample identified in this report.

Approved by Authorized Signatory:

Kurt Chen / Q.A. Manager

Accredited Lab. of NEMKO, A2LA, BSMI

Listed Lab. of FCC, VCCI, MOC

A2LA Certificate #: 824.01 (for Emission) NEMKO Authorization #: ELA 124 (for EMC) Page 5

Rev. 00





EMC COMPLIANCE TEST REPORT

for

Panel PC (IPC)

Trade Name : N/A Model Number : G3000 Serial Number : N/A Report Number: 000560-E Date : August 16, 2000 Regulations : See below

Standards	Results (Pass/Fail)
EN 55022: 1994 + A1: 1995 + A2: 1997 (Class A)	PASS
EN 60555-2: 1987	PASS
EN 61000-3-3: 1995	PASS
EN 50082-2: 1995	PASS
- EN 61000-4-2: 1995	PASS
- ENV 50140: 1994	PASS
- ENV 50204: 1996	PASS
- EN 61000-4-4:1995	PASS
- ENV 50141: 1994	PASS
- EN 61000-4-8: 1993	N/A

Prepared for:

AASIC Computer Inc. 4F-1, No. 131, Lane 235, Pao Chiao Rd., Hsin Tien, Taipei Shian, Taiwan, R.O.C.

Prepared by:



C&C LABORATORY CO., LTD. #B1, 1st Fl., Universal Center, No. 183, Sec. 1, Tatung Rd., Hsi Chih, Taipei Hsien, Taiwan, R.O.C.

TEL: (02) 86422071 FAX: (02) 86422256

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Accredited Lab. of NEMKO, A2LA, BSMI Listed Lab. of FCC, VCCI, MOC

A2LA Certificate #: 824.01 (for Emission) NEMKO Authorization #: ELA 124 (for EMC)

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Rev. 00





EC-Declaration of Conformity

For the following equipment:		
Panel PC (IPC)		
(Product Name)		
G3000		
(Model Designation / Trade name)		
AASIC Computer Inc.		
(Manufacturer Name) 4F-1, No. 131, Lane 235, Pao Chiao	Rd., Hsin Tien, Taipei Shian, Taiwan, R.	O.C.
(Manufacturer Address)		
Approximation of the Laws of the (89/336/EEC, Amended by 92/31.	with the requirements set out in the Co Member States relating to Electroma /EEC & 93/68/EEC), For the evalua inded by 92/31/EEC & 93/68/EEC), the	gnetic Compatibility Directive tion regarding the Electromagnetic
 V EN 55022: 1994 + A1: 1995 V EN 60555-2: 1987 V EN 61000-3-3: 1995 V EN 50082-2: 1995 EN 61000-4-2: 1995; ENV ENV 50141: 1994 	+ A2: 1997 (Class A) 50140: 1994; ENV 50204: 1996; EN	61000-4-4: 1995
The following manufacturer / impresponsible for this declaration:	orter or authorized representative esta	blished within the EUT is
(Company Name)		
(Company Address)		
Person responsible for making this	s declaration:	
(Name, Surname)		
(Position / Title)		
(Place)	(Date)	(Legal Signature)
Accredited Lab. of NEMKO, A2LA, BSMI		Page 2
Listed Lab. of FCC, VCCI, MOC	A2LA Certificate #: 824.01 (for Emission) NEMKO Authorization #: ELA 124 (for EMC)	Rev. 00



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GENERAL INFORMATION

Applicant:

AASIC Computer Inc.

4F-1, No. 131, Lane 235, Pao Chiao Rd., Hsin Tien,

Taipei Shian, Taiwan, R.O.C.

Contact Person:

Shun-Han Chang

Manufacturer:

AASIC Computer Inc.

4F-1, No. 131, Lane 235, Pao Chiao Rd., Hsin Tien,

Taipei Shian, Taiwan, R.O.C.

File Number:

000560-E

Date of Test:

August 3 ~ 9, 2000

Equipment Under Test:

Panel PC (IPC)

Model Number:

G3000

Serial Number:

N/A

Technical Standards:

EN 55022: 1994 + A1: 1995 + A2: 1997 (Class A)

EN 60555-2: 1987, EN 61000-3-3: 1995

EN 50082-2: 1995 (EN 61000-4-2: 1995, ENV 50140: 1994,

ENV 50141: 1994, EN 61000-4-4: 1995,

ENV 50204: 1996)

Frequency Range

(EN 55022):

150kHz to 30MHz for Line Conducted Test

30MHz to 1000MHz for Radiated Emission Test

Test Site

C & C LABORATORY CO., LTD.

No. 15, 14 Lin, Chi Twu Chi, Lu-Chu Hsiang

Taoyuan, Taiwan, R. O. C.



SYSTEM DESCRIPTION

EUT Test Program:

- 1. EMI test program was loaded and executed in Windows mode
- 2. A communication software was loaded and executed to drive LAN, then to communicate with remote side.
- 3. Data was sent to LCD Panel of EUT and CRT monitor, filling the screen with upper case of "H" patterns.
- 4. Test program sequentially exercised all related I/O's of EUT and send "H" patterns to all applicable ports of EUT.
- 5. Repeat 2 to 3. Test program is self-repeating throughout the test.



PRODUCT INFORMATION

Housing Type:

Metal case

EUT Power Rating:

100-240VAC, 3.15A, 47-62Hz

AC Power during Test

230VAC/50Hz

Power Supply Manufacturer:

POWER ADD, INC.

Power Supply Model Number:

PPS100-31

AC Power Cord Type:

Unshielded, 1.8m (Detachable) with a core

CPU Manufacture:

Intel

Celeron 433MHz Type:

OSC/Clock Frequencies:

66MHz

Install: 64MB

Memory Capacity: HDD Manufacturer:

Toshiba

Model: HDD2130

FDD Manufacturer:

NEC Toshiba Model: FD1238T

Model: NRP28-8875-413

VGA Card Manufacturer:

12.1" TFT LCD Panel Manufacturer:

On Board

I/O Port of EUT

I/O PORT TYPES	Q'TY	TESTED WITH
1) Parallel Port	1	1
2) Serial Port	3	3
3) Video Port	1	1
4) PS/2 Keyboard Port	1	1
5) PS/2 Mouse Port	1	1
6) Microphone Port	1	1
7) Line-in Port	1	1
8) Line-out Port	1	1
9) LAN Port	1	1
10) USB Port	2	2



SUPPORT EQUIPMENT (for EN 55022 only)

No.	o. Equipment Model Serial # #				Trade Name	Data Cable	Power Cord
1.	Monitor	GDM-17SE2T	7139819	AK8GDM17SE2T	SONY	Shielded, 1.8m	Unshielded, 1.8m
2.	Printer	2225C	3137S01428	DSI6XU2225	HP	Shielded, 1.8m	Unshielded, 1.8m
3.	Modem	103/212A	A038518	EF56A5103/212A	TEAM	Shielded, 1.8m	Unshielded, 1.8m
4.	Modem	2400	94-364-176276	DK467GSM24	Computer Peripherals	Shielded, 1.8m	Unshielded, 1.8m
5.	Modem	2400 94-364-176277 DK467GSM24 Computer		Computer Peripherals	Shielded, 1.8m	Unshielded, 1.8m	
6.	PS/2 Keyboard	SK-2502C	M99043551	FCC DoC	HP Shielded,		N/A
7.	PS/2 Mouse	M-S34	LZC84445540	DZL211029	HP	Shielded, 1.8m	N/A
8.	USB Mouse	M-BB48	LZE1450642	FCC DoC	Logitech	Shielded, 1.8m	N/A
9.	USB Mouse	M-BB48	LZE1450904	FCC DoC	C Logitech Shielded,		N/A
10.	Walkman	YX-328	YX-328 W2 N/A YING-KO		Unshielded, 1.8m	N/A	
11.	Multimedia Headset	SX-M	A5-4	A5-4 N/A T		Unshielded, 1.8m	N/A
12.	Notebook PC (Remote)	365	TZ30518	FCC D ₀ C	Acer	Shielded, 20m with a core	AC I/P: Unshielded, 0.9n DC O/P: Unshielded, 1.9n

Note: All the above equipment/cables were placed in worse case positions to maximize emission signals during emission test.

Grounding: Grounding was in accordance with the manufacturer's requirements and conditions for the intended use.



SUPPORT EQUIPMENT (for all test except EN 55022)

No.	-1		Serial	FCC	Trade Name	Data Cable	Power
		# #		ID	Name	Cable	Cord
1.	Monitor	D2827A	KR92316215	C5F7NFCMC1518X	HP	Shielded, 1.8m	Unshielded, 1.8m
2.	Printer	2225C	3137S01428	DSI6XU2225	HP	Shielded, 1.8m	Unshielded, 1.8m
3.	Modem	103/212A	A038518	EF56A5103/212A	TEAM	Shielded, 1.8m	Unshielded, 1.8m
4.	Modem	2400	94-364-176276	DK467GSM24	Computer Peripherals	Shielded, 1.8m	Unshielded, 1.8m
5.	Serial Mouse	M-MM43	LZE93353024	DoC	Logitech	Shielded, 1.8m	N/A
6.	PS/2 Keyboard	SK-2502C	M99043551	FCC DoC	HP	Shielded, 1.8m	N/A
7.	PS/2 Mouse	M-S34	LZC84445540	DZL211029	НР	Shielded, 1.8m	N/A
8.	USB Mouse	M-BB48	LZE1450642	FCC DoC	Logitech	Shielded, 1.8m	N/A
9.	USB Mouse	e M-BB48 LZE1450904		FCC DoC	Logitech	Shielded, 1.8m	N/A
10.	Walkman	YX-328	W2 N/A		YING-KO	Unshielded, 1.8m	N/A
11.	Multimedia Headset	SX-M	M A5-4	SX-M A5-4 N/A	токуо	Unshielded, 1.8m	N/A
12.	Notebook PC (Remote)	365	TZ30518	FCC DoC	Acer	Shielded, 20m	AC I/P: Unshielded, 0.9m DC O/P: Unshielded, 1.9m

Note: All the above equipment/cables were placed in worse case positions to maximize emission signals during emission test.

Grounding: Grounding was in accordance with the manufacturer's requirements and conditions for the intended use.



TEST FACILITY

Location: No. 15, 14 Line, Chin Twu Chi, Lu Chu Hsiang, Taoyuan, Taiwan,

R.O.C.

Description: There are four 3/10m open area test sites and three line conducted labs for

The Open Area Test Sites and the Line Conducted labs are constructed and calibrated to meet the FCC requirements in documents ANSI C63.4: 1992

and CISPR 22/EN 55022 requirements.

Site Filing: A site description is on file with the Federal Communications

Commission, 7435 Oakland Mills Road, Columbia, MD 21046.

Registration also was made with Voluntary Control Council for

Interference (VCCI).

Site Accreditation: Accredited by NEMKO (Authorization #: ELA 124) for EMC &

A2LA (Certificate #: 824.01) for Emission

Also accredited by BSMI for the product category of Information

Technology Equipment.

Instrument Tolerance: All measuring equipment is in accord with ANSI C63.4 and CISPR 22

requirements that meet industry regulatory agency and accreditation

agency requirement.

Two conductive reference ground planes were used during the Line Conducted **Ground Plane:** Emission, one in vertical and the other in horizontal. The dimensions of these ground planes are as below. The vertical ground plane was placed distancing 40 cm to the rear of the wooden test table on where the EUT and the support equipment were placed during test. The horizontal ground plane projected 50 cm beyond the footprint of the EUT system and distanced 80 cm to the wooden test table. For Radiated Emission Test, one horizontal conductive ground plane extended at least 1m beyond the periphery of the EUT and the largest measuring antenna, and covered the entire area between the EUT and the antenna. It has no holes or gaps having longitudinal dimensions larger than one-tenth of a wavelength at the highest frequency of measurement up to 1GHz.

Site # 1 & # 3 Line Conducted Test Site: Vertical ground plane (2.2m x 2.2m)

Horizontal ground plane (2.5m x 2.5m)

Site # 4 Line Conducted Test Site: At Shielding Room

Accredited Lab. of NEMKO, A2LA, BSMI Listed Lab. of FCC, VCCI, MOC

A2LA Certificate #: 824.01 (for Emission)

NEMKO Authorization #: ELA 124 (for EMC)

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THE AMERICAN
ASSOCIATION
FOR LABORATORY
ACCREDITATION

ACCREDITED LABORATORY

A2LA has accredited

C & C LABORATORY CO., LTD Taipei, Taiwan, R.O.C

for technical competence in the field of

Electrical (EMC) Testing

The accreditation covers the specific tests and types of tests listed on the agreed scope of accreditation. This laboratory meets the requirements of ISO/IEC Guide 25-1990 "General Requirements for the Competence of Calibration and Testing Laboratories" (equivalent to relevant requirements of the ISO 9000 series of standards) and any additional program requirements in the identified field of testing.

Presented this 28th day of April, 2000.

SEAL STATE

President / For the Accreditation Council Certificate Number 824.01 Valid to January 31, 2002

For tests or types of tests to which this accreditation applies, please refer to the laboratory's Electrical (EMC) Scope of Accreditation



SCOPE OF ACCREDITATION TO ISO/IEC GUIDE 25-1990 and EN 45001-1989

C & C LABORATORY CO., LTD No. 15, 14 Lin, Chin Twu Chi Lu Chu Hsiang, Taoyuan, TAIWAN, R.O.C. Charles Wang Phone: 002 886 3 324 5966 Fax: 002 886 3 324 5235

ELECTRICAL (EMC)

Valid to: January 31, 2002

Certificate Number: 0824-01

In recognition of the successful completion of the A2LA evaluation process, accreditation is granted to this laboratory to perform the following tests:

Electrical Emissions – Enclosure – 3 & 10 Meters; to 26.5 GHz (Sites 1, 2, 3 and 4) Electrical Emissions – AC Power – 0 - 300 V; 50 - 400 Hz (Sites 1, 2, 3 and 4) Electrical Immunity - Enclosure - 27 - 80 MHz / 3V/m; 80 MHz - 1 GHz / 10V/m Electrical Immunity - AC Power, DC Power, Signal & Control Electrical Fast Transient (EFT) Electrostatic Discharge (ESD) to 25 kV **Electrical Power Surge** Power Magnetic Field Immunity Voltage Dips, Shots, Variations

On the following products/equipment:

Computer Components and Peripherals; Networking Components; Wireless Communications Components; Electronic Components; Televisions; Home Appliances

Using the following test methods/specifications/standards:

Code of Federal Regulations (CFR) 47, FCC Part 15 using ANSI C63.4 AS/NZS 3548 BSMI CNS: 13438, 13439, 13783, 13803

CISPR: 11, 14, 22

EN: 50081-1, 50082-1, 55011, 55022, 55014, 61000-4-2, 61000-4-3, 61000-4-4, 61000-4-5, 61000-4-6,

61000-4-8, 61000-4-11

VCCI V3 (1999)

IEC: 801-2, 801-3, 801-4

Peter Rhye



FEDERAL COMMUNICATIONS COMMISSION Equipment Authorization Division 7435 Oakland Mills Road Columbia, MD. 21046

February 01, 1999

Registration Number: 93105

C & C Laboratory Co., Ltd. 1st Fl., No. 344, Fu Ching Street Taipei Taiwan, R.O.C.

Attention:

Charles Wang

Re.

Measurement facility located at Taoyuan, Site No. 4

3 & 10 meters

Date of Listing: February 01, 1999

Gentlemen:

Your submission of the description of the subject measurement facility has been reviewed and found to be in compliance with the requirements of Section 2.948 of the FCC Rules. The description has, therefore, been placed on file and the name of your organization added to the Commission's list of facilities whose measurement data will be accepted in conjunction with applications for Certification under Parts 15 or 18 of the Commission's Rules. Please note that this filing must be updated for any changes made to the facility, and at least every three years from the date of listing the data on file must be certified as current.

If requested, the above mentioned facility has been added to our list of those who perform these measurement services for the public on a fee basis. An up-to-date list of such public test facilities is available on the Internet on the FCC Website at WWW.FCC.GOV, Electronic Filing, OET Equipment Authorization Electronic Filing.

Sincerely,

Thomas W Phillips Electronics Engineer

FEDERAL COMMUNICATIONS COMMISSION

7435 Oakiand Milts Road Columbia, MD 21046 Telephone: 301-725-1585 (ext-218) Facsimile: 301-344-2050

April 20, 1998

NREPLY REFER TO 31040/SIT 1300F2

C&C Laboratory Co., Ltd. 1st Fl., No. 344, Fu Ching Street Taipei, Taiwan

Attention:

Charles Wang

Re: Measurement facility located at Taoyuan, Site No. 3 (3 and 10 meter site)

Gentlemen:

Your submission of the description of the subject measurement facility has been reviewed and found to be in compliance with the requirements of Section 2.948 of the FCC Rules. The description has, therefore, been placed on file and the name of your organization added to the Commission's list of facilities whose measurement data will be accepted in conjunction with applications for certification or notification under Parts 15 or 18 of the Commission's Rules. Our list will also indicate that the facility complies with the radiated and AC line conducted test site criteria in ANSI C63.4-1992. Please note that this filing must be updated for any changes made to the facility, and at least every three years the data on file must be certified as current.

Per your request, the above mentioned facility has been also added to our list of those who perform these measurement services for the public on a fee basis. This list is updated monthly and is available on the Laboratory's Public Access Link (PAL) at 301-725-1072, and also on the Internet at the FCC Website www.fcc.gov/oet/info/database/testsite/.

Sincerely.

Thomas W. Phillips Electronics Engineer

2hm Whitly

Customer Service Branch

FEDERAL COMMUNICATIONS COMMISSION

7435 Oakland Mills Road Columbia, MD 21046 Telephone: 301-725-1585 (ext-218) Facsimile: 301-344-2050

March 13, 1998

IN REPLY REFER TO 31040/SIT 1300F2

C & C Laboratory Co., Ltd. 1st Fl., No. 344, Fu Ching Street Taipei, Taiwan

Attention:

Ceres Lin

Re: Measurement facility located at Taoyuan (3 and 10 meter site)

Gentlemen:

Your submission of the description of the subject measurement facility has been reviewed and found to be in compliance with the requirements of Section 2.948 of the FCC Rules. The description has, therefore, been placed on file and the name of your organization added to the Commission's list of facilities whose measurement data will be accepted in conjunction with applications for certification or notification under Parts 15 or 18 of the Commission's Rules. Our list will also indicate that the facility complies with the radiated and AC line conducted test site criteria in ANSI C63.4-1992. Please note that this filling must be updated for any changes made to the facility, and at least every three years the data on file must be

Per your request, the above mentioned facility has been also added to our list of those who perform these measurement services for the public on a fee basis. This list is updated monthly and is available on the Laboratory's Public Access Link (PAL) at 301-725-1072, and also on the Internet at the FCC Website www.fcc.gov/oet/info/database/testsite/.

Sincerely,

Thomas W. Phillips Electronics Engineer

Customer Service Branch



ENG 3/9 AJD

22 January 1998

C & C Laboratory Co Ltd 1st FI No. 344 Fu Ching Street Taipei TAIWAN ROC

Attention: Mr Tony Houng

Dear Sir

LABORATORY APPROVAL

Thank you for your submission of 21 January regarding the approval of your testing laboratory to the Ministry of Commerce's laboratory approval criteria. Thank you for your interest in this matter.

I am pleased to advise that your submission has been successful and your laboratory has been added to the list of Ministry-approved laboratories. Your approved status is valid until 31 December 1998. At this time, the Approved Laboratory scheme will cease operation with the implementation of the new radiocommunications regulations. Test reports from your laboratory will be accepted under the new framework. Please find enclosed a copy of the Ministry's discussion paper, DP10, outlining the proposed compliance process from 1 January 1999.

If you have any further questions on this matter please do not hesitate to contact me.

Yours faithfully

Andrew Dyke

Senior Technical Officer(Regulatory)



World-wide Testing and Certification

ELA 4

EMC Laboratory Authorisation

Aut. No.: ELA 160

EMC Laboratory:

C & C Laboratory Co., Ltd. No. 15, 14 Lin, Chin Twu Chi, Lu Chu Hsiang,

Taoyuan 338, Taiwan R.O.C.

Scope of Authorization:

EN 60601-1-2 and IEC 60601-1-2, the Collateral Standards for electromedical products, with particular application to EMC requirements only.

This Authorisation Document confirms that the above mentioned EMC Laboratory has been validated against EN 45001 and found to be compliant. The laboratory also fulfils the conditions described in Nemko Document ELA 10. During Nemko's visit to the laboratory on 14 and 15 May, 1999, an assessment was made of the relevant parts of your organisation i.e. facilities, personnel qualifications, test equipment, and testing practices. It was found that the EMC Laboratory is capable of performing tests within the Scope of Authorisation listed above. Accordingly, Nemko will accept your test reports as a basis for attesting conformity to these EMC Standards for the products in question under either the European Union Medical Device Directive [MDD], 93/42/EEC, or the European Union Active Implantable Medical Device Directive [AIMD], 90/385/EEC, (as applicable).

In case of applications for Product Certification(s) to be issued by Nemko, your EMC Laboratory's test report(s) will be accepted by Nemko if they are enclosed with the Application Form submitted by the manufacturer.

In order to maintain the Authorisation, the information given in the enclosed ELA-INFOs (if any) must be carefully followed. Nemko is to be promptly notified about any changes in the situation at your EMC Laboratory which may affect the basis for this Authorisation. The Authorisation may at any time be withdrawn if the conditions are no longer considered to be fulfilled.

The Authorisation is valid through 30 September, 2000.

Oslo, 29 September 1999

For Nemko AS:

Kjell Bergh, Nemko Group EMC Co-ordinator

P.O.Box 73 Blindern

Telephone: +47 22 96 63 36

Fax:

+47 22 96 85 50



World-wide Testing and Certification

ELA 4

EMC Laboratory Authorisation

Aut. No. : ELA 124

EMC Laboratory:

C & C Laboratory Co., Ltd.

No. 15, 14 Lin, Chin Twu Chi, Lu Chu Hsiang,

Taoyuan 338, Taiwan R.O.C.

Scope of Authorization: All CENELEC standards [ENs] for EMC that are listed on the accompanying page, and, all of the corresponding CISPR, IEC, and ISO EMC standards that are listed on the

accompanying page.

This Authorisation Document confirms that the above mentioned EMC Laboratory has been validated against EN 45001 and found to be compliant. The laboratory also fulfils the conditions described in Nemko Document ELA 10. During Nemko's visit to the laboratory on 14 and 15 May, 1999, an assessment was made of the relevant parts of your organisation - i.e. facilities, personnel qualifications, test equipment, and testing practices. It was found that the EMC Laboratory is capable of performing tests within the Scope of Authorisation given on the accompanying page. Accordingly, Nemko will accept your test reports as a basis for attesting conformity to these EMC Standards for the products in question under the European Union EMC Directive [89/336/EEC as amended by 92/31/EEC and 98/13/EC].

In case of applications for Product Certification(s) to be issued by Nemko, your EMC Laboratory's test report(s) will be accepted by Nemko if they are enclosed with the Application Form submitted by the manufacturer.

In order to maintain this Authorization, the information given in the enclosed ELA-INFOs (if any) must be carefully followed. Nemko is to be promptly notified about any changes in the situation at your EMC Laboratory which may affect the basis for this Authorization. The Authorization may at any time be withdrawn if the conditions are no longer considered

The Authorisation is valid through 30 September, 2000.

Oslo, 29 September 1999

For Nemko AS:

Kjell Bergh, Nemko Group EMC Co-ordinator

P.O.Box 73 Ba

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World-wide Testing and Cortification

ELA 4

EMC Laboratory Authorisation

Aut. No.: ELA 124 (Page 2 of 2)

SCOPE OF AUTHORIZATION

GENERIC & PRODUCT-FAMILY STANDARDS

	NO 045-045-2415-	이번 가장 그림
EN 50081-1(1992)	EN 50081-2(1994)	EN 50082-1(1992), EN 50082-1(1997)
EN 50082-2(1995)	EN 50091-2(1995)	EN 50130-4(1995)
CISPR 11(1990), CISPR 11(1997), EN 55011(1991), EN 55011(1998)	CISPR 13(1975)+ A1(1983) EN55013(1990) +A12(1994) + A13(1996)	CISPR 14(1993) + A1(1993) + Corrigendum(1996) [Excluding Clause 4.2] EN 55014-1(1993) + A1(1997) [Excluding Clause 4.2]
CISPR 14-2(1997), EN 55014-2(1997) EN 55104(1995)	CISPR 15(1992), CISPR 15(1996) +A1(1997), EN 55015(1996) + A1(1997)	CISPR 24(1997), EN 55024(1998)
CISPR 22(1993) +A1(1995) +A2(1997). EN 55022(1994) + A1(195) + A2(1997) CISPR 22(1997) [Excluding Clause 9.5] EN 55022(1998) [Excluding Clause 9.5]	EN 60555-2(1987), EN 61000-3-2(1995)+A1(1998) + A2 (1998)	EN 60555-3(1987) + A1(1991), EN 61000-3-3(1995)
IEC 61326-1(1997), EN 61326-1(1997)		

BASIC STANDARDS

IEC 801-2(1984), IEC 61000-4-2(1991) IEC/EN 61000-4-2(1995)	IEC 801-3(1984), IEC/EN 61000-4-3(1995) ENV 50204(1995)	IEC 801.4(1988), IEC/EN 61000-4-4(1995)
IEC/EN 61000-4-5(1995) [Including Corrigendum]	IEC/EN 61000-4-6(1996)	IEC/EN 61000-4-8(1993/94)
IEC/EN 61000-4-11(1994)		

Oslo, 29 September 1999

Kjell Bergh, Nemko Group EMC Co-ordinator

N-4314 OSLO, NORWAY

+47 22 96 05 50



Technischer Überwachungs-Verein Rheinland

Certificate

of

The applicant:

C & C Laboratory Co., Ltd.

No. 15, 14 Lin, Chin twu Chi, Lu Chu Hsiang, Taoyuan, Taiwan, R.O.C.

has been authorized to carry out EMC tests by order and under supervision of TÜV Rheinland according to

EN 55 011:1991, EN 55 014-1:1993/A1, EN 55 022:1994/A1, EN 55 014-2:1997, EN 60 555-2:1987, EN 61 000-3-2:1995, EN 61 000-3-3:1995
EN 50 081-1:1992, EN 50 082-1:1992, EN 50 082-1:1997, EN 50 081-2:1993
EN 50 082-2:1995, IEC 801-2:1984, IEC 801-2:1991, IEC 801-3:1984
IEC 801-4:1988, IEC 801-5:1990, EN 61 000-4-2:1995, ENV 80 140:1993, ENV 50 141:1993 ENV 50 204:1995, EN 61 000-4-3:1996, EN 61 000-4-4:1995, EN 61 000-4-5:1995 EN 61 000-4-6:1995, EN 61 000-4-8:1993, EN 61 000-4-11:1994

An inspection of the facility was conducted according to the Document "Approval of Test Site" with reference to EN 45 001 by a TÜV Rheinland inspector.

Audit Report No. P 9964142E01, Rev.-This certificate is valid until the next scheduled inspection or up to 15 month, at the discretion of TÜV Rheinland.

> TÜV Rheinland Taiwan Ltd. Taipei, 24. June 1999

Dipl.-Ing. A. Klinker

£6

Dipl.-Ing. R. Charton

Auditor



中華民國經濟部標準檢驗局

量先市海南路一段四號

BUREAU OF STANDARDS, METROLOGY AND INSPECTION MINISTRY OF ECONOMIC AFFAIRS. REPUBLIC OF CHINA 4, SEC, 1, CHINAN ROAD, TAIPEI, TAIWAN, R. O. C. Tel: 886-2-23431700 FAX: 886-2-23932324

To: C&C Laboratory Co., Ltd

IN REPLY REFER TO 87-2-01386

1 Fl.No.344, Fu Ching St., Taipei, Taiwan

This Designation Document confirms that your subject measurement facility has been validated according to the ISO/IEC Guide 25-1990 and found to be in compliance with the requirements of "Operation Guidelines of the Approval and Management of Designated EMC Laboratories."

The description of your facility has, therefore, been placed on file and the name of your organization added to the Bureau's list of facilities whose measurement data and test reports will be accepted as a basis for attesting conformity to CNS13438-1994 / CISPR22-1993, CNS13783-1-1996/ CISPR14 - 1993, CNS13439-1997 / CISPR13-1990 for Information Technology Equipment • household appliances/tools • broadcast receivers and related equipments.

It is located at: http://ww

Please reference are file numbers below in the body of airmeasurements made on the corresponding facility.

rts containing

For your <u>EMI Testing Lab</u>, use reference "SL2-IN-E-001 2-A1 0014, SL2-R1-E-0014, SL2-R2-E-0014"

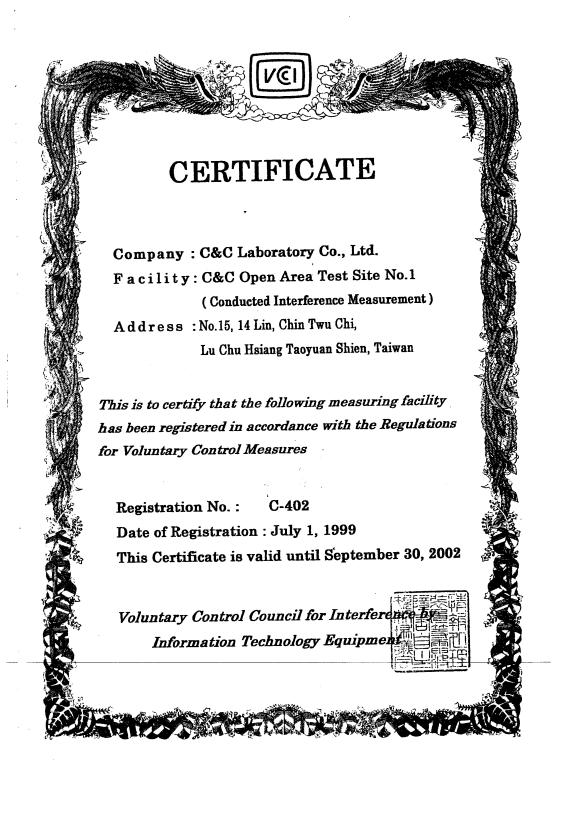
Note that this filing must be updated for any changes your documentation and / or facility and whenever major solution or major construction or repairs to your facility are completed, re-submission of the related information or the site attenuation characteristics will be required within 2 weeks.

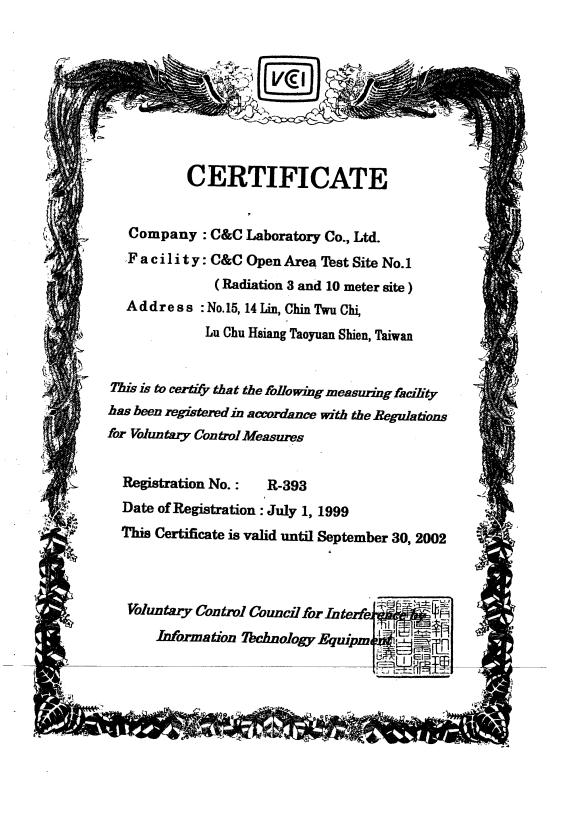
The Designation is valid through January 16, 2001.

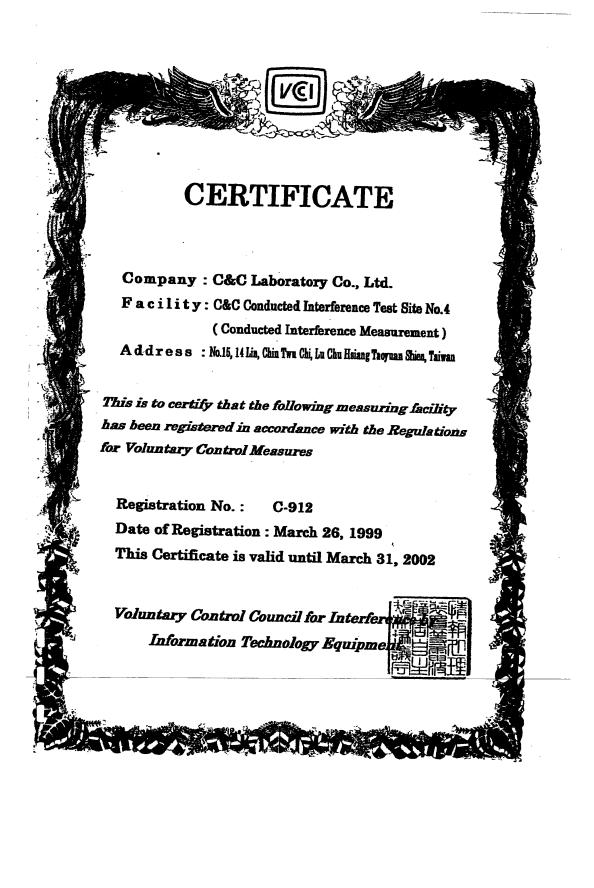
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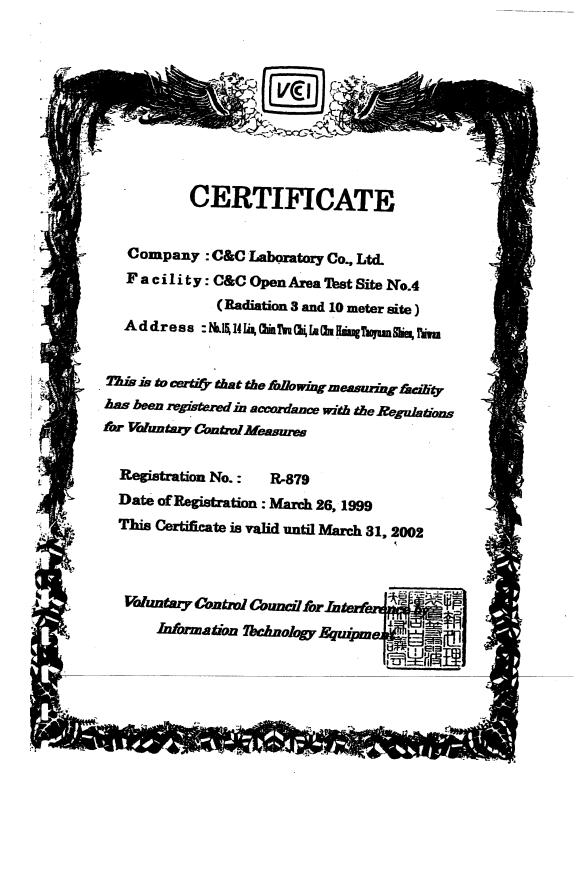
Taipei, October 5, 1999 For BSMI, MOEA

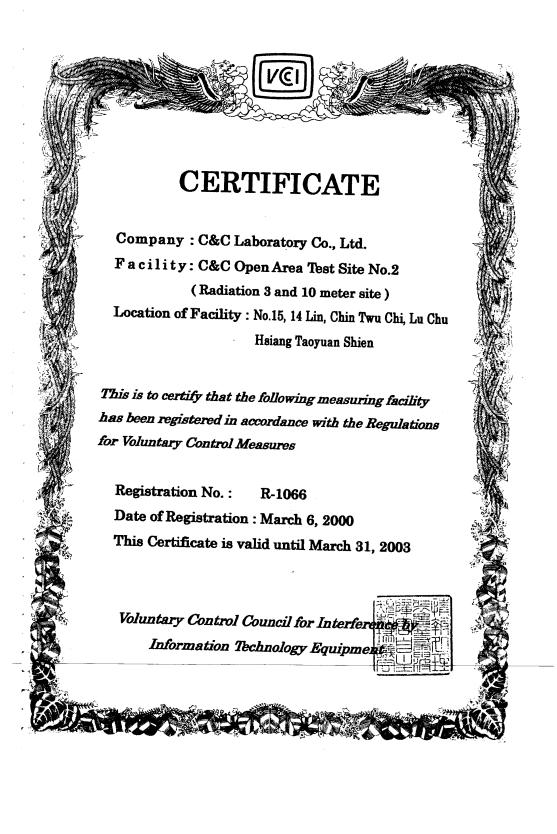
Chen Tso-Chen



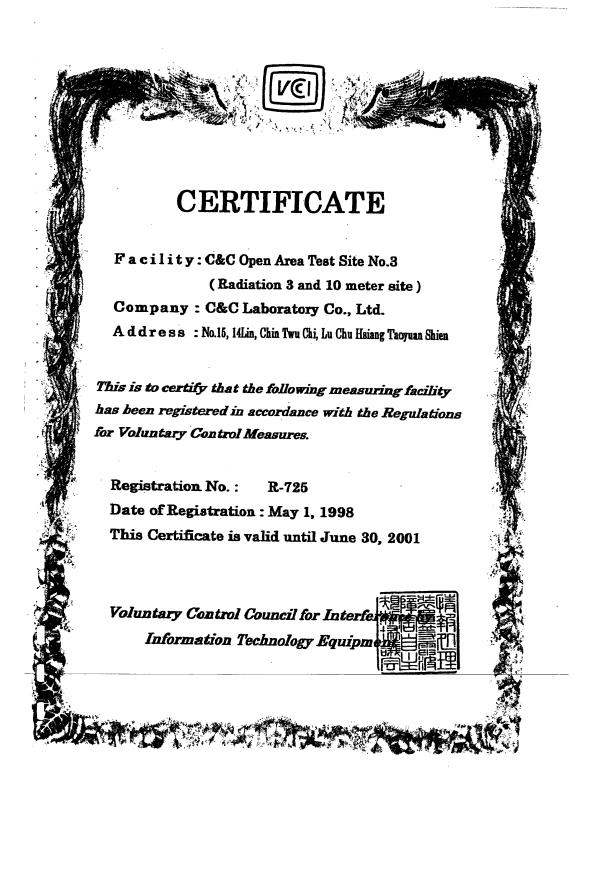














Chinese National Laboratory Accreditation Certificate ROC 中華民國實驗室認證體系認可證書

No.CNLA-ZL98078

程智科技服份有限公司程智科技電磁相容實驗室之電性測試領域經評鑑認可

十項發給本證書有效期限至九十年十一月十四日 此證

This is to certify that C & C Laboratory Co., Ltd. hardbeen recognized by the Council of Chinese National Laboratory Accreditation as an accreditationy. The laboratory has been registered for ten specific tests within the field of Ectrical Festing. The details of the scope of accreditation is described in the following pages and this Certificate is valid until Nov. 14, 2001.

中華民國實驗宣認證委員會 主 任 泰 章

Chen, Ming-Bang

The Chairman of Chinese National Laboratory Accreditation Council

(本種書共 4 原分學使用無效This document is invalid unless accompanied by all 4 pages.) 丽

4 Page 2 of No.CNLA-ZL98678

機能である。 の表現の を表現の のである。 のでは、 のでは、

Organization: C&CLaboratory Co., Ltd.
Laboratory: C&CLaboratory Co., Ltd.
Registration: 0363
Laboratory Head: WANG, Charles
Testing Field: Electrical Testing
Date of Registration: 1998.11.15

		-														
備群	Remarks													-		
認可之 最佳測試能力	Best test	capability recognized														
国 強	Range		御試件職整:100~2 MAC(軍相) 。 即試件重流:0~16	副校校阅读:1~40		《件電腦:100~270VAC(單相)	V 01~0~10 V			, 1	海域十級:150 kHz~30 MBz	THE TYPE OF THE TY		(電道	報料干擾:30 MHz~2.0 GHz	
御試方法	spouper				· · · ·			is and								
翼	Test		LEC 1000-3-2(1995) EN 61000-3-2(1995)			IEC 1000-3-3(1994)	C887 \2-2-00079 vs				CISPR 22(1996)	CNS 13438(1997)	MS/NZS 3548(1995)	PCC Pert 15(1996)		
演就作	Test items		資訊類及其選 達正 品 ITE and peripheral	Products		250103 實際聯聯的開催工 [72]	Products				E10122 實信及發酵技術系 Iffe and navighers	Products		-		
認可項目	Registration	items	EN0102 器效電流干援	Harmonic current Products	emissions	EJ0103	W W W W W W W W W W W W W W W W W W W	Voltage	fluctuations and	flicker	E10122 電信及機関技術系	統及鐵器	Systems and	apparatus of the	telecommunicatio	n and

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Page 3

No.CMLA-ZL98078

編 群 Remarks 認可之**最佳測試**能力 Best test capability recognized 空間放電: 0.2 kV~16.5 kV(+/-) 接觸放電:0.2 kV~9.0 kV(+/-) 7.5 W REPORT 26 NR - 1.0 GR.

MAR - 1.0 V n. ANDRON

Section 1.0 GR.

Report 1.0 GR. 類字質問:150 kHz~230 kHz (振幅:10 V,AK調整) ၏ Range 建新政権 1 A/m~100 A/m 觀試方法 Test methods IEC 801-3(1984)
IEC 1000-4-3(1995)
EN 61000-4-3(1996)
ENY 50204(1995) ENV 50142(1994) CNS 13022-3(1992) EN 61060-4-2(1995) EN 61060-4-2(1995) CNS 13022-1(1992) IEC 801-4(1988) IEC 1000-4-4(1995 EN 61000-4-4(1995 CNS 13022-2(1992) LEC 1080-4-8(1993) EN 61000-4-8(1993) LEC 1080-4-6(1993) EN 61000-4-6(1996) 資制模及其**建達產品** ITE and peripheral Products 資訊類及其運邊產品 ITE and peripheral Products 實訊權及其**連建在**品 [TE and peripheral Products 渔就作 Test items E10204 電性快速突波測試 ITE and peripheral Electrical fast Products EJ0205 資訊規及其選議產品 突被/雷擊湖試 ITE and peripheral Surge/lightening Products E10208 電源頻率磁場耐受 ITE and peripheral 認可項目 Registration discharge tests E10203 輻射耐受測試 Electrical fast transient/burst E10202 靜電放電測試 susceptibility susceptibility Electrostatic EJ0206 傳導耐受測試 Conducted items information technology Radieted tests tests tests tests

4		
Page 4 of	番 註 Remarks	
No.CNI.A-ZLSB978 Pag	認可之最佳測試能力 Best test capability recognized	
No.CML	範 翼 Range	T #: 100%
	測試方法 Test methods	IEC 1000-4-11(1994) EN 61000-4-11(1994)
	測試件 Test terms	Products Bower frequency magnetic field immunity test L10211 E10211 E20211 E20
	認 可項目 Registration items	Math Power frequency magnetic field immunity test EJ0211 機種下降・解析和 Math Math Math Math Math Math Math Math



TEST EQUIPMENT LIST

Instrumentation: The following list contains equipment used at C & C Laboratory, Co., Ltd. for testing. The equipment conforms to the CISPR 16-1 / ANSI C63.2-1988 Specifications for Electromagnetic Interference and Field Strength Instrumentation from 10kHz to 1.0 / 2.0 GHz.

Equipment used during the tests:

Open Area Test Site:	\square #1; V #2; \square #3; \square #4
Open med rest site.	

	_				A SAKAS PAR
	Ор	en Area Test	Site # 1	104	1,000
EQUIPMENT TYPE	MFR	MODEL NUMBER	SERIAL NUMBER	LAST CAL.	CAL. DUE
Q.P Adaptor	HP	85650A	2811A01399	05/05/2000	05/04/200
RF Pre-selector	HP	85685A	2947A01064	05/05/2000	05/04/200
Spectrum Analyzer	HP	8568B	3001A05004	05/05/2000	05/04/200
S.P.A Display	HP	8568B	3014A18846	05/05/2000	05/04/200
Precision Dipole	R&S	HZ-12	846932/0004	07/14/2000	07/13/200
Precision Dipole	R&S	HZ-13	846556/0008	07/14/2000	07/13/200
Bilog Antenna	CHASE	CBL6112A	2309	02/13/2000	02/12/200
Turn Table	EMCO	2081-1.21	N/A	N.C.R	N.C.R
Antenna Tower	EMCO	2075-2	9707-2604	N.C.R	N.C.R
Controller	EMCO	2090	N/A	N.C.R	N.C.R
RF Switch	ANRITSU	MP59B	M54367	N.C.R	N.C.R
Site NSA	C&C	N/A	N/A	11/10/1999	11/09/200

Open Area Test Site # 2								
EQUIPMENT TYPE	MFR	MODEL NUMBER	SERIAL NUMBER	LAST CAL.	CAL. DUE			
Spectrum Analyzer	ADVANTEST	R3261C	81720301	09/02/1999	09/01/2000			
Pre-Amplifier	HP	8447D	2944A08432	11/16/1999	11/15/2000			
EMI Test Receiver	R&S	ESVS10	834468/006	03/24/2000	03/23/2001			
Precision Dipole	R&S	HZ-12	846932/0004	07/14/2000	07/13/2001			
Precision Dipole	R&S	HZ-13	846556/0008	07/14/2000	07/13/2001			
Bilog Antenna	CHASE	CBL 6112A	SITE2	12/10/1999	12/09/2000			
Turn Table	Chance Most	CM-T003-1	T807-6	N.C.R	N.C.R			
Antenna Tower	Chance Most	CM-A003-1	A807-6	N.C.R	N.C.R			
Controller	Chance Most	N/A	N/A	N.C.R	N.C.R			
RF Switch	ANRITSU	MP59B	M76890	N.C.R	N.C.R			
Site NSA	C&C Lab.	N/A	N/A	11/13/1999	11/12/2000			

Accredited Lab. of NEMKO, A2LA, BSMI Listed Lab. of FCC, VCCI, MOC

A2LA Certificate #: 824.01 (for Emission) NEMKO Authorization #: ELA 124 (for EMC) Page 12

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	Open Area Test Site #3								
EQUIPMENT TYPE	MFR	MODEL NUMBER	SERIAL NUMBER	LAST CAL.	CAL. DUE				
Spectrum Analyzer	ADVANTEST	R3261C	71720533	10/25/1999	10/24/2000				
Pre-Amplifier	HP	8447D	2944A09173	02/01/2000	01/31/2001				
EMI Test Receiver	R&S	ESVS20	838804/004	12/24/1999	12/23/2000				
Precision Dipole	R&S	HZ-12	846932/0004	07/14/2000	07/13/2001				
Precision Dipole	R&S	HZ-13	846556/0008	07/14/2000	07/13/2001				
Bilog Antenna	CHASE	CBL6112A	2179	11/27/1999	11/26/2000				
Turn Table	EMCO	2081-1.21	9709-1885	N.C.R	N.C.R				
Antenna Tower	EMCO	2075-2	9707-2060	N.C.R	N.C.R				
Controller	EMCO	2090	9709-1256	N.C.R	N.C.R				
RF Switch	ANRITSU	MP59B	M53867	N.C.R	N.C.R				
Site NSA	C&C	N/A	N/A	01/30/2000	01/29/2001				

EQUIPMENT TYPE	MFR	MODEL NUMBER	SERIAL NUMBER	LAST CAL.	CAL. DUE
Spectrum Analyzer	ADVANTEST	R3132	91700456	02/15/2000	02/14/2001
Pre-Amplifier	HP	8447F	2944A03748	10/22/1999	10/21/2000
EMI Test Receiver	R&S	ESCS30	845552/030	12/04/1999	12/03/2000
Precision Dipole	R&S	HZ-12	846932/0004	07/14/2000	07/13/2001
Precision Dipole	R&S	HZ-13	846556/0008	07/14/2000	07/13/2001
Bilog Antenna	CHASE	CBL 6112B	2462	01/13/2000	01/12/2001
Turn Table	Chance most	N/A	N/A	N.C.R	N.C.R
Antenna Tower	Chance most	N/A	N/A	N.C.R	N.C.R
Controller	Chance most	N/A	N/A	N.C.R	N.C.R
RF Switch	ANRITSU	MP59B	M51067	N.C.R	N.C.R
Site NSA	C&C Lab.	N/A	N/A	12/26/1999	12/25/2000

Conducted Emission Test Site:

#4

Conducted Emission Test Site #4						
EQUIPMENT TYPE	MFR	MODEL NUMBER	SERIAL NUMBER	LAST CAL.	CAL. DUE	
EMI Test Receiver	R&S	ESHS10	843743/015	12/10/1999	12/09/2000	
LISN	EMCO	3825/2	9003/1382	01/10/2000	01/09/2001	
LISN	R&S	ESH2-Z5	843250/010	12/06/1999	12/05/2000	

The calibrations of the measuring instruments, Inc.luding any accessories that may effect such calibration, are checked frequently to assure their accuracy. Adjustments are made and correction factors applied in accordance with instructions contained in the manual for the measuring instrument.

Accredited Lab. of NEMKO, A2LA, BSMI Listed Lab. of FCC, VCCI, MOC

A2LA Certificate #: 824.01 (for Emission) NEMKO Authorization #: ELA 124 (for EMC)

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TEST EQUIPMENT LIST

For Power Harmonic & Voltage Fluctuation/Flicker Measurement:

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Manufacturer/Type	Model No.	Serial No.	Last Cal.	Cal. Due		
HAEFELY TRENCH	PHF 555	080 419-25	Oct. 05, 1999	Oct.04, 2000		
Harmonic & Flicker Tester		1	,			

For ESD test:

Manufacturer/Type	Model No.	Serial No.	Last Cal.	Cal. Due
EMV SYSTEME/	SESD 2000	812006	Nov. 19, 1999	Nov. 18, 2000
ESD Generator	SESD 2000	612000	1107. 19, 1999	1101. 10, 2000

For Radiated Electromagnetic Field immunity Measurement:

ror Radiated Electroniagnetic Field initiality intenserous					
Manufacturer/Type	Model No.	Serial No.	Last Cal.	Cal. Due	
Maconi /Signal Generator	2022D	119246/003	Aug. 17, 1999	Aug. 16, 2000	
M2S / Power Amplifier	A00181/1000	9801-112	N/A	N/A	
M2S / Power Amplifier	AC8113/800-250A	9801-179	N/A	N/A	
Wandel & Goltormann/ EM-Radiation Meter	EMR-30	L-0013	02/25/2000	02/24/2001	
EMCO Power Antenna	93141	9712-1083	N/A	N/A	

For Fast Transients/Burst test:

Manufacturer/Type	Model No.	Serial No.	Last Cal.	Cal. Due
HAEFELY TRENCH/ Fast Transients/Burst	PEFT-JUNIOR	583 333-117	Aug. 18, 1999	Aug. 17, 2000
Generator				

For CS test:

Manufacturer/Type	Model No.	Serial No.	Last Cal.	Cal. Due
Maconi /Signal Generator	2022D	119246/003	Aug. 17, 1999	Aug. 16, 2000
MEB / CDN M3	M3	3683	Sep. 09, 1999	Sep. 08, 2000
M2S / Power Amplifier	A00181/1000	9801-112	N/A	N/A



SECTION 1 EN 55022 (LINE CONDUCTED & RADIATED EMISSION)

MEASUREMENT PROCEDURE (PRELIMINARY LINE CONDUCTED EMISSION TEST)

- 1) The equipment was set up as per the test configuration to simulate typical actual usage per the user's manual. When the EUT is a tabletop system, a wooden table with a height of 0.8 meters is used and is placed on the ground plane as per EN 55022 (see Test Facility for the dimensions of the ground plane used). When the EUT is a floor-standing equipment, it is placed on the ground plane which has a 3-12 mm non-conductive covering to insulate the EUT from the ground plane.
- 2) Support equipment, if needed, was placed as per EN 55022.
- 3) All I/O cables were positioned to simulate typical actual usage as per EN 55022.
- 4) The EUT received AC power through a Line Impedance Stabilization Network (LISN) which supplied power source of 230VAC/50Hz and was grounded to the ground plane.
- All support equipment received power from a second LISN supplying power of 110VAC/60Hz, if any.
- 6) The EUT test program was started. Emissions were measured on each current carrying line of the EUT using a spectrum Analyzer / Receiver connected to the LISN powering the EUT. The LISN has two monitoring points: Line 1 (Hot Side) and Line 2 (Neutral Side). Two scans were taken: one with Line 1 connected to Analyzer / Receiver and Line 2 connected to a 50 ohm load; the second scan had Line 1 connected to a 50 ohm load and Line 2 connected to the Analyzer / Receiver.
- 7) Analyzer / Receiver scanned from 150kHz to 30MHz for emissions in each of the test modes.
- 8) During the above scans, the emissions were maximized by cable manipulation.
- 9) The following test mode(s) were scanned during the preliminary test:

Mode(s):

- 1. 800 x 600 Resolution
- 2. 640 x 480 Resolution
- 10) After the preliminary scan, we found the following test mode producing the highest emission level.

Mode: 1.

Then, the EUT configuration and cable configuration of the above highest emission level were recorded for reference of final testing.

Accredited Lab. of NEMKO, A2LA, BSMI

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A2LA Certificate #: 824.01 (for Emission) NEMKO Authorization #: ELA 124 (for EMC)

Rev. 00

Listed Lab. of FCC, VCCI, MOC



MEASUREMENT PROCEDURE (FINAL LINE CONDUCTED EMISSION TEST)

- 1) EUT and support equipment was set up on the test bench as per step 10 of the preliminary test.
- 2) A scan was taken on both power lines, Line 1 and Line 2, recording at least the six highest emissions. Emission frequency and amplitude were recorded into a computer in which correction factors were used to calculate the emission level and compare reading to the applicable limit.
- 3) The test data of the worst case condition(s) was reported on the Summary Data page.

Data Sample:

Freq. MHz	Q.P. Raw dBuV	Average Raw dBuV	Q.P. Limit dBuV	Average Limit dBuV	Q.P. Margin dB	Average Margin dB	Note
x.xx	43.95		56	46	-12.05	-2.05	L 1

Freq. = Emission frequency in MHz

Raw dBuV = Uncorrected Analyzer/Receiver reading

Limit dBuV = Limit stated in standard

Margin dB = Reading in reference to limit

Note = Current carrying line of reading

= The emission level complied with the Average limits,

with at least 2 dB margin, so no further recheck.

LINE CONDUCTED EMISSION LIMIT

Frequency	Maximum RF Line Voltage		
	Q.P.	AVERAGE	
150kHz-500kHz	79dBuV	66dBuV	
500kHz-5MHz	73dBuV	60dBuV	
5MHz-30MHz	73dBuV	60dBuV	

Note: The lower limit shall apply at the transition frequency.

Accredited Lab. of NEMKO, A2LA, BSMI Listed Lab. of FCC, VCCI, MOC

A2LA Certificate #: 824.01 (for Emission) NEMKO Authorization #: ELA 124 (for EMC) Page 16



MEASUREMENT PROCEDURE (PRELIMINARY RADIATED EMISSION TEST)

- 1) The equipment was set up as per the test configuration to simulate typical actual usage per the user's manual. When the EUT is a tabletop system, a wooden turntable with a height of 0.8 meters is used which is placed on the ground plane as per EN 55022 (see Test Facility for the dimensions of the ground plane used). When the EUT is a floor-standing equipment, it is placed on the ground plane which has a 3-12 mm non-conductive covering to insulate the EUT from the ground plane.
- 2) Support equipment, if needed, was placed as per EN 55022.
- 3) All I/O cables were positioned to simulate typical actual usage as per EN 55022.
- 4) The EUT received 230VAC/50Hz power source from the outlet socket under the turntable. All support equipment received 110VAC/60Hz power from another socket under the turntable, if any.
- 5) The antenna was placed at some given distance away from the EUT as stated in EN 55022. The antenna connected to the Analyzer via a cable and at times a pre-amplifier would be used.
- 6) The Analyzer / Receiver quickly scanned from 30MHz to 1000MHz. The EUT test program was started. Emissions were scanned and measured rotating the EUT to 360 degrees and positioning the antenna 1 to 4 meters above the ground plane, in both the vertical and the horizontal polarization, to maximize the emission reading level.
- 7) The following test mode(s) were scanned during the preliminary test:

Mode(s):

- 1. 800 x 600 Resolution
- 2. 640 x 480 Resolution
- 8) After the preliminary scan, we found the following test mode producing the highest emission level.

Mode: 1.

Then, the EUT and cable configuration, antenna position, polarization and turntable position of the above highest emission level were recorded for final testing.



MEASUREMENT PROCEDURE (FINAL RADIATED EMISSION TEST)

- 1) EUT and support equipment were set up on the turntable as per step 8 of the preliminary test.
- 2) The Analyzer / Receiver scanned from 30MHz to 1000MHz. Emissions were scanned and measured rotating the EUT to 360 degrees, varying cable placement and positioning the antenna 1 to 4 meters above the ground plane, in both the vertical and the horizontal polarization, to maximize the emission reading level.
- 3) Recorded at least the six highest emissions. Emission frequency, amplitude, antenna position, polarization and turntable position were recorded into a computer in which correction factors were used to calculate the emission level and compare reading to the applicable limit and only Q.P. reading is presented.
- 4) The test data of the worst case condition(s) was reported on the Summary Data page.

Data Sample:

Freq.	Raw Data	Corr. Factor	Emiss. Level	Limits	Margin	
(MHz)	(dBuV/m)	(dB)	(dBu	V/m)	(dB)	
xx.xx	14.0	11.2	26.2	30	-3.8	
Freq.			= Emission	frequency in I	МНz	
Raw Data	(dRuV/m)		= Emission frequency in MHz = Uncorrected Analyzer / Receiver reading			
Corr. Factor (dB)			= Correction factors of antenna factor and cable los			
				= Raw reading converted to dBuV and CF added		
Emice Las	امر		- Paw read		to dBuV and CF added	
Emiss. Lev	/el		= Raw read	ing converted	to dBuV and CF added	

= Reading in reference to limit

Margin dB

Report Number: 000560-E August 16, 2000



RADIATED EMISSION LIMIT

Frequency (MHz)	Distance (m)	Maximum Field Strength Limit (dBuV/m/ Q.P.)
30-230	10	40
230-1000	10	47

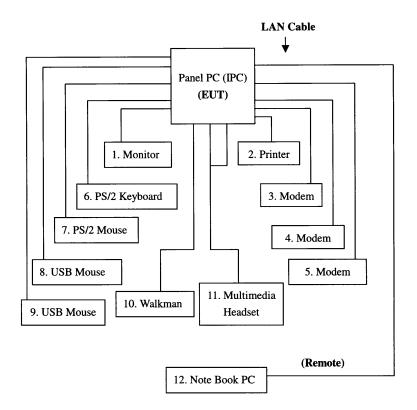
Note: The lower limit shall apply at the transition frequency.



BLOCK DIAGRAM OF TEST SETUP

SYSTEM DIAGRAM OF CONNECTIONS BETWEEN EUT AND SIMULATORS

EUT: Panel PC (IPC)
Trade Name: N/A
Model Number: G3000
Power Cord: Unshielded, 1.8m



Accredited Lab. of NEMKO, A2LA, BSMI Listed Lab. of FCC, VCCI, MOC

A2LA Certificate #: 824.01 (for Emission) NEMKO Authorization #: ELA 124 (for EMC) Page 20



SUMMARY DATA (LINE CONDUCTED TEST)

Location: Site #4 Model Number: G3000

Tested by: Tony Tsai

Test Mode: Mode 1

Test Results: Passed

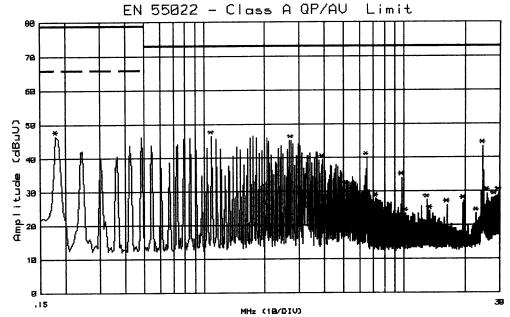
Temperature: 29⁰C Humidity: 66%RH

(The chart below shows the highest readings taken from the final data)

FREQ.	Q.P. RAW dBuV	AVG RAW dBuV	Q.P. Limit dBuV	AVG Limit dBuV	Q.P. Margin dB	AVG Margin dB	NOTE
0.180	45.2		79.0	66.0	-33.8		Ll
1.090	45.1		73.0	60.0	-27.9		L1
2.730	43.3		73.0	60.0	-29.7		L1
3.940	38.2		73.0	60.0	-34.8		Ll
6.500	37.9		73.0	60.0	-35.1		Ll
24.580	41.5		73.0	60.0	-31.5		L1
0.150	64.9		79.0	66.0	-14.1		L2
1.700	51.6		73.0	60.0	-21.4		L2
3.216	49.0		73.0	60.0	-24.0		L2
5.180	49.1		73.0	60.0	-23.9		L2
6.500	60.1		73.0	60.0	-12.9		L2
9.750	55.3		73.0	60.0	-17.7		L2

L1 = Line One (Hot side) / L2 = Line Two (Neutral side)
**NOTE: "---" denotes the emission level was or more than 2dB below the Average limit, so no re-check anymore.

C&C Lab. Co. Shielded Room4



'ustomer:NA

Date : 9 Aug 2000 18:39:47 Temp. :29 (C) Tester:TONY TSAI

riodel :G3000

File#: 2611 Humd.:66 (%) Port :L1

Mode

Mode :FULL SYSTEM

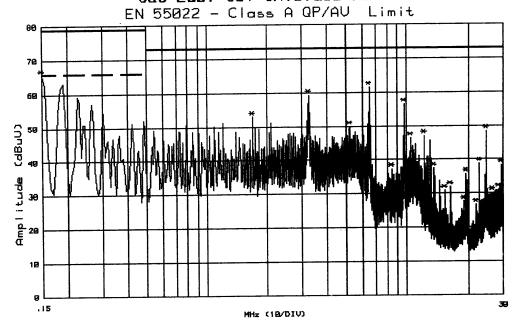
eading :Peak(R&S Receiver)

emark :LEARNING AGE

* 10.	Freq.	Reading (dBuV)	I_Loss (dB)	Total (dBuV)	QP.Lmt (dBuV)	Margin (dB)	Warning Mark
1	.180	46.4	.1	46.5	79.0	-32.5	
2	1.090	46.3	.2	46.5	73.0	-26.5	
3	2.730	44.9	.3	45.1	73.0	-27.9	
4	3.940	39.1	.3	39.4	73.0	-33.6	
5	6.500	39.5	.5	40.0	73.0	-33.0	
6	7.280	27.3	.5	27.8	73.0	-45.2	
7	9.750	33.6	.5	34.1	73.0	-38.9	
- 8	10.250	22.6	.8	23.4	73.0	-49.6	
9	13.010	26.6	.8	27.4	73.0	-45.6	
1 0	13.340	23.3	.8	24.1	73.0	-48.9	
11	16.260	24.9	1.0	25.9	73.0	-47.1	
.2	19.530	26.0	1.0	27.0	73.0	-46.0	
3	22.760	22.2	1.1	23.3	73.0	-49.7	
14	24.580	42.2	1.1	43.3	73.0	-29.7	
- 5	26.010	28.1	1.3	29.4	73.0	-43.6	

C&C	Lab. Co. Ltd.
File No.	000560-E
Page	21-1

C&C Lab. Co. Shielded Room4



Justomer:NA
Model :G3000

File#: 2612 Humd.:66 (%) Port :L2

Mode :FULL SYSTEM
Reading :Peak(R&S Receiver)
Remark :LEARNING AGE

Date : 9 Aug 2000 18:57:06 Temp. :29 (C) Tester:TONY TSAI

٧o.	Freq.	Reading (dBuV)	I_Loss (dB)	Total (dBuV)	QP.Lmt (dBuV)	Margin (dB)	Warning Mark
1 2 3 4 5 6 7 8 9 10 11	.150 1.700 3.260 5.180 6.500 8.430 9.750 10.510 12.290 13.560 15.290 16.260	65.6 52.8 59.0 49.6 61.2 37.0 56.2 46.1 46.6 37.0 30.2 31.2	.1 .2 .2 .3 .3 .3 .3 .4 .4 .4	65.7 53.0 59.2 49.9 61.5 37.3 56.5 46.5 47.0 37.4 30.8 31.8	79.0 73.0 73.0 73.0 73.0 73.0 73.0 73.0 73	-13.3 -20.0 -13.8 -23.1 -11.5 -35.7 -16.5 -26.5 -26.0 -35.6 -42.2 -41.2	
13 14 15	18.940 19.490 21.840	27.0 35.1 26.0	.6 .6 .6	27.6 35.7 26.6	73.0 73.0 73.0	-45.4 -37.3 -46.4	

C&C	Lab. Co. Ltd.
File No.	000560-E
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SUMMARY DATA (RADIATED EMISSION TEST)

Model Number: G3000 Location: Site # 2

Tested by: Michael Chen

Test Mode: Mode 1 Polar: Vertical -- 10m

Detector Function: Quasi-Peak Test Results: Passed

Temperature: 30°C **Humidity:** 72%RH

(The chart below shows the highest readings taken from the final data)

Freq. (MHz)	Raw Data (dBuV/m)	Corr. Factor (dB)	Emiss. Level (dBuV	Limits //m)	Margin (dB)
50.75	26.3	9.1	35.4	40.0	-4.6
66.32	26.8	7.4	34.2	40.0	-5.8
117.05	23.4	14.3	37.7	40.0	-2.3
167.01	23.6	12.4	36.0	40.0	-4.0
434.50	16.0	22.8	38.8	47.0	-8.2
507.42	16.4	24.5	40.9	47.0	-6.1



SUMMARY DATA (RADIATED EMISSION TEST)

Model Number: G3000 Location: Site # 2

Tested by: Michael Chen

Test Mode: Mode 1 Polar: Horizontal -- 10m

Detector Function: Quasi-Peak **Test Results:** Passed

Temperature: 30°C **Humidity:** 72%RH

(The chart below shows the highest readings taken from the final data)

Freq. (MHz)	Raw Data (dBuV/m)	Corr. Factor (dB)	Emiss. Level (dBu	Limits V/m)	Margin (dB)
66.42	26.1	7.4	33.5	40.0	-6.5
89.75		11.0	37.3	40.0	-2.7
117.04	23.3	14.3	37.6	40.0	-2.4
167.02	25.0	12.4	37.4	40.0	-2.6
434.50	21.5	22.8	44.3		-2.7
507.49	18.9	24.5	43.4	47.0	-3.6



EN 61000-3-2 & EN 61000-3-3 (POWER HARMONICS **SECTION 2** & VOLTAGE FLUCTUATION/FLICKER)

POWER HARMONICS MEASUREMENT

: AC mains Port

: EN 61000-3-2: 1995 +A1: 1998 + A2: 1998 **Basic Standard**

: V Class A, Class D Limits

: Kevin Wang Tester

Temperature : 30℃ Humidity : 40%

: The Class A limits of EN 61000-3-2 was used to instead of EN 60555-2 Deviation

limits.

VOLTAGE FLUCTUATION/FLICKER MEASUREMENT

: AC mains Port

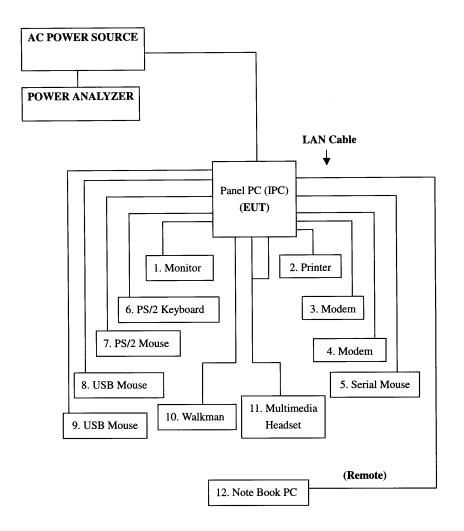
: EN 61000-3-3 (1995) **Basic Standard** : §5 of EN 61000-3-3 Limits

Tester : Kevin Wang

: 30℃ Temperature : 40% Humidity

Block Diagram of Test Setup:





Result:

Please see the attached test data.

Report Number: 000560-E August 16, 2000



EN 61000-3-2 TEST REPORT 2000/8/9 03:04 PM

Unit:

Panel PC (IPC)

Serial No.:

G3000

Remarks:

Temp: 30°C

Humidity: 40%

Operator:

KEVIN

TEST SETUP

Test Freq.:

50.00 Hz. Test Voltage: 230.0 vac

Waveform:

SINE

Test Time:

2.5 min.

Classification:

CLASS A

Test Type:

STEADY-STATE

Prog. Zo Enabled:

YES

Prog. Zo:

0.000

Motor Driven with Phase Angle Control: NO

Impedance selected:

DIRECT

Synthetic R+L Enabled:

NO

Resistance: 0.380 Ohms

Inductance: 460.000 uH

Max Watts: 83.9W

Accredited Lab. of NEMKO, A2LA, BSMI Listed Lab. of FCC, VCCI, MOC

A2LA Certificate #: 824.01 (for Emission) NEMKO Authorization #: ELA 124 (for EMC)

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TEST DATA

Result:

PASS

Harmonic Current Results

Hn	AMPS	LO Limit	HI Limit	Result
0	0.000	0.000	0.000	PASS
1	0.373	NaN	NaN	PASS
2	0.027	1.080	1.080	PASS
3	0.213	2.300	2.300	PASS
4	0.004	0.430	0.430	PASS
5	0.185	1.140	1.140	PASS
6	0.003	0.300	0.300	PASS
7	0.172	0.770	0.770	PASS
8	0.002	0.230	0.230	PASS
9	0.153	0.400	0.400	PASS
10	0.002	0.184	0.184	PASS
11	0.130	0.330	0.330	PASS
12	0.001	0.153	0.153	PASS
13	0.108	0.210	0.210	PASS
14	0.001	0.131	0.131	PASS
15	0.084	0.150	0.150	PASS
16	0.001	0.115	0.115	PASS
17	0.063	0.132	0.132	PASS
18	0.001	0.102	0.102	PASS
19	0.043	0.118	0.118	PASS
20	0.001	0.092	0.092	PASS
21	0.026	0.107	0.107	PASS

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22	0.001	0.084	0.084	PASS
23	0.013	0.098	0.098	PASS
24	0.001	0.077	0.077	PASS
25	0.008	0.090	0.090	PASS
26	0.001	0.071	0.071	PASS
27	0.011	0.083	0.083	PASS
28	0.000	0.066	0.066	PASS
29	0.014	0.078	0.078	PASS
30	0.000	0.061	0.061	PASS
31	0.015	0.073	0.073	PASS
32	0.000	0.058	0.058	PASS
33	0.014	0.068	0.068	PASS
34	0.000	0.054	0.054	PASS
35	0.011	0.064	0.064	PASS
36	0.000	0.051	0.051	PASS
37	0.008	0.061	0.061	PASS
38	0.000	0.048	0.048	PASS
39	0.004	0.058	0.058	PASS
40	0.000	0.046	0.046	PASS

END OF REPORT



EN 61000-3-3 TEST REPORT 2000/8/9 03:18 PM

.....

Unit:

Panel PC (IPC)

Serial No.:

G3000

Remarks:

Temp: 30℃

Humidity: 40%

Operator:

KEVIN

TEST SETUP

Test Freq.:

50.00 Hz. Test Voltage:

230.0 vac

Waveform: Test Time: SINE

10.0 min.

Tshort:

10.0 min.

Prog. Zo Enabled:

YES

Prog. Zo:

0.000

Voltage Change less than once per Hour:

NO

Impedance selected:

DIRECT

Synthetic R+L Enabled:

NO

Resistance: 0.380 Ohms

Inductance: 460.000 uH



TEST DATA

Result:	PASS			
	EUT Data	Limit	Result	Test Enabled
Pst max	0.001	1.00	PASS	t rue
Plt max	0.001	0.65	PASS	t rue
dc %	0.00	3.00	PASS	true
dmax %	0.00	4.00	PASS	t rue
d(t) sec.	0.00	0.20	PASS	true

Power Source Data Source Pst max 0.020 0.400 PASS true % THD 0.03 3.00 PASS true

END OF REPORT



SECTION 3 EN 61000-4-2 (ELECTROSTATIC DISCHARGE)

ELECTROSTATIC DISCHARGE (ESD) IMMUNITY TEST

Port : Enclosure

Basic Standard : EN 61000-4-2

Requirements : ±8kV (Air Discharge)

 $\pm 4kV$ (Contact Discharge)

±4kV (Indirect Discharge)

Performance Criteria: B (Standard Required)

Tested by : Kevin Wang **Temperature/Humidity**: 30^oC / 40%

Block Diagram of Test Setup:

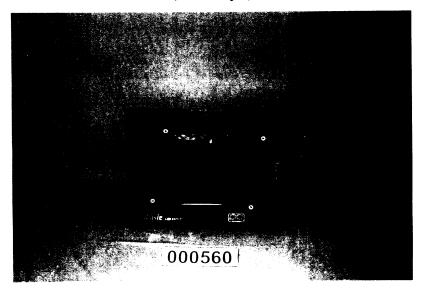
Accredited Lab. of NEMKO, A2LA, BSMI Listed Lab. of FCC, VCCI, MOC

A2LA Certificate #: 824.01 (for Emission) NEMKO Authorization #: ELA 124 (for EMC) Page 31

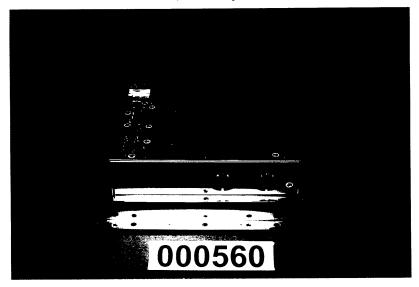
CNLA 0363

The Tested Points of EUT

(Photo 1 of 5)



(Photo 2 of 5)

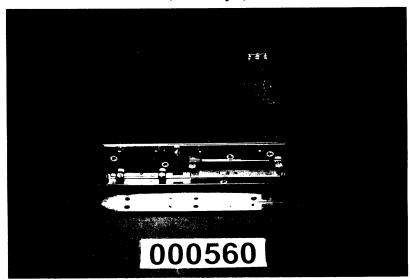


Accredited Lab. of NEMKO, A2LA, BSMI Listed Lab. of FCC, VCCI, MOC

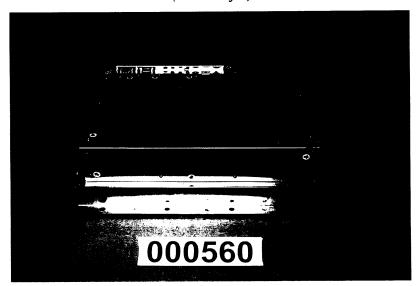
A2LA Certificate #: 824.01 (for Emission) NEMKO Authorization #: ELA 124 (for EMC) Page 34



(Photo 3 of 5)



(Photo 4 of 5)

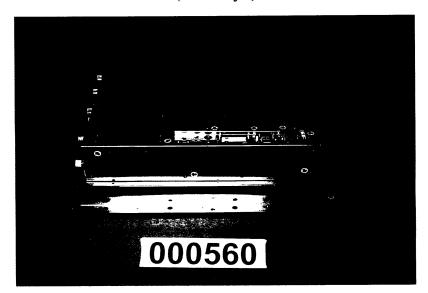


Accredited Lab. of NEMKO, A2LA, BSMI Listed Lab. of FCC, VCCI, MOC

A2LA Certificate #: 824.01 (for Emission) NEMKO Authorization #: ELA 124 (for EMC) Page 35



(Photo 5 of 5)





SECTION 4 ENV 50140 (RADIATED ELECTROMAGNETIC FIELD)

RADIATED ELECTROMAGNETIC FIELD IMMUNITY TEST

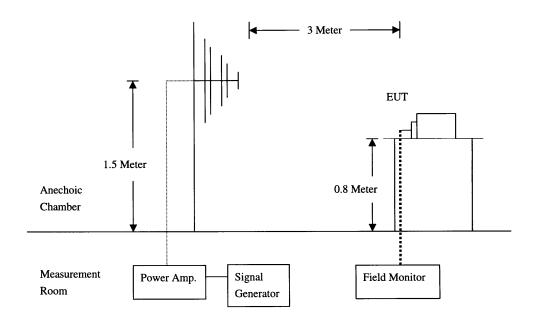
Port : Enclosure
Basic Standard : ENV 50140

Requirements : 10 V/m, with Modulated
Performance Criteria : A (Standard Required)

 $\begin{tabular}{lll} \textbf{Tested by} & : Peter Lee \\ \textbf{Temperature} & : 27^0C \\ \textbf{Humidity} & : $51\% \\ \end{tabular}$

Block Diagram of Test Setup:

Same as Section 3 EN61000-4-2 Test Setup:



Accredited Lab. of NEMKO, A2LA, BSMI Listed Lab. of FCC, VCCI, MOC

A2LA Certificate #: 824.01 (for Emission) NEMKO Authorization #: ELA 124 (for EMC) Page 37

Report Number: 000560-E August 16, 2000



Test Procedure:

Frequency Range : 80MHz-1000MHz : 1% of fundamental Frequency Step

Dwell Time : 3 sec

Range (MHz)	Field	Modulation	Polarity	Position (°)	Reside(Page Fail)
80-1000	10V	Yes	Н	0	Pass
80-1000	10V	Yes	V	0	Pass
80-1000	10V	Yes	Н	90	Pass
80-1000	10V	Yes	V	90	Pass
80-1000	10V	Yes	Н	180	Pass
80-1000	10V	Yes	V	180	Pass
80-1000	10V	Yes	Н	270	Pass
80-1000	10V	Yes	V	270	Pass

Performance & Result:

V Criteria A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
Criteria B:	The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
Criteria C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.
**Observation: 1	No any function degraded during the tests.



SECTION 5 ENV 50204 (RADIATED ELECTROMAGNETIC FIELD FROM **DIGITAL TELEPHONES**)

RADIATED ELECTROMAGNETIC FIELD IMMUNITY TEST

Port

: Enclosure

Basic Standard

: ENV 50204

Requirements

: 10 V/m, with modulated Performance Criteria: A (Standard Required)

Tested by

: Peter Lee

Temperature

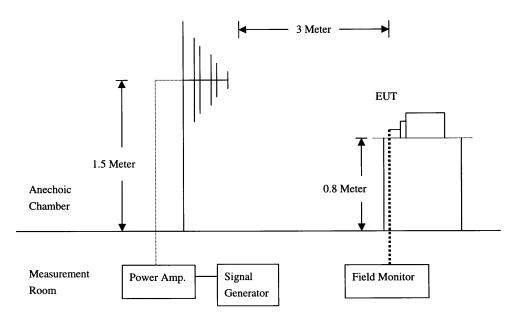
: 27°C

Humidity

:51%

Block Diagram of Test Setup:

Same as Section 3 EN61000-4-2 Test Setup:



Accredited Lab. of NEMKO, A2LA, BSMI

Listed Lab. of FCC, VCCI, MOC

A2LA Certificate #: 824.01 (for Emission) NEMKO Authorization #: ELA 124 (for EMC)

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Test Procedure:

Spot Frequency : 900 MHz ±5MHz

Modulated Frequency : 200 Hz Duty cycle : 50%

Range (MHz)	Field	Modulation	Polarity	Position (b)	Resulf(DESTER)
900	10V	Yes	Н	0	Pass
900	10V	Yes	V	0	Pass
900	10V	Yes	Н	90	Pass
900	10V	Yes	V	90	Pass
900	10V	Yes	Н	180	Pass
900	10V	Yes	V	180	Pass
900	10V	Yes	Н	270	Pass
900	10V	Yes	V	270	Pass

Performance & Result:

V Criteria A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
Criteria B:	The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
Criteria C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.
**Observation: 1	No any function degraded during the tests.



SECTION 6 EN 61000-4-4 (FAST TRANSIENTS/BURST)

FAST TRANSIENTS/BURST IMMUNITY TEST

: On Power Supply Lines **Port**

: EN 61000-4-4 **Basic Standard**

: ±2kV for Power Supply Line Requirements

: 40%

±1kV for Data Cable

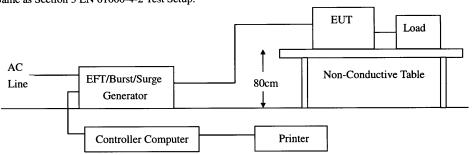
Performance Criteria: B (Standard require)

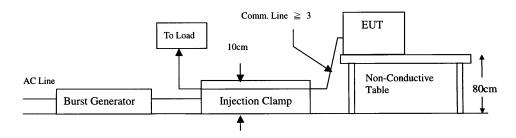
: Kevin Wang Tested by : 30°C **Temperature**

Block Diagram of Test Setup:

Humidity

Same as Section 3 EN 61000-4-2 Test Setup:





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A2LA Certificate #: 824.01 (for Emission) NEMKO Authorization #: ELA 124 (for EMC) Page 41



Test Procedure:

Impulse Frequency: 5kHz
Tr/Th:: 5/50ns
Burst Duration:: 15ms
Burst Period:: 3Hz

Inject Line	Voltage kV	Inject Method	Result (Pass/Fail)
L1	±2	Direct	Pass
N	±2	Direct	Pass
PE	±2	Direct	Pass
L1 + N	±2	Direct	Pass
L1 + PE	±2	Direct	Pass
N + PE	±2	Direct	Pass
L1 + N + PE	±2	Direct	Pass
LAN Cable	±1	Clamp	Pass

Performance & Result:

V Criteria A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
Criteria B:	The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
Criteria C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.
**Observation:	No any function degraded during the tests.



SECTION 7 ENV 50141 (CONDUCTED DISTURBANCE/INDUCED BY RADIO-FREQUENCY FIELD)

Port

: Power cord and Data bus

Basic Standard

: ENV 50141

Requirements

: 10 V with Modulated

Injection Method

: CDN-M3 for Power core EM-Clamp for LAN cable

Livi-Clain

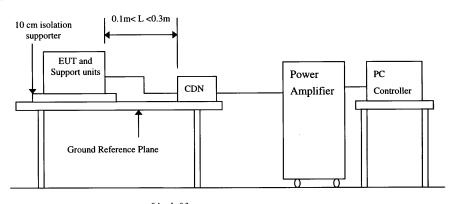
Performance Criteria: A

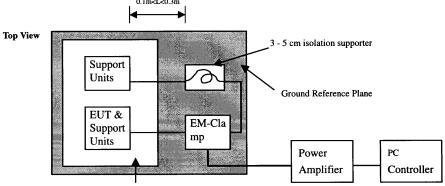
Tested by Temperature : Peter Lee : 27°C

Humidity

: 51%

Block Diagram of Test Setup:





Accredited Lab. of NEMKO, A2LA, BSMI Listed Lab. of FCC, VCCI, MOC

A2LA Certificate #: 824.01 (for Emission) NEMKO Authorization #: ELA 124 (for EMC) Page 43

Report Number: 000560-E August 16, 2000



Test Procedure:

Frequency Range : 0.15MHz-80MHz : 1% of fundamental Frequency Step

Dwell Time : 3 sec

Range (MHz)	Field	Modulation	Result (Pass/Fail)
0.15-80	10V	Yes	Pass

Performance & Result:

V Criteria A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.	
Criteria B:	The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.	
Criteria C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.	
**Observation: No any function degraded during the tests.		



SECTION 9 EN 61000-4-8 (POWER FREQUENCY MAGNETIC FIELD IMMUNITY TEST)

Port : Enclosure

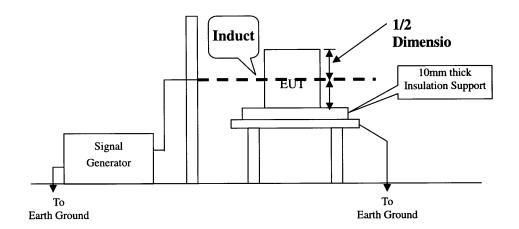
Basic Standard : EN 61000-4-8

Requirements : 3 A/m

Performance Criteria: A (Standard Required)

Temperature : N/A Humidity : N/A

Block Diagram of Test Setup:





Test Procedure:

Field Strength: 3A/m Power Freq.: 50Hz Orientation: X, Y, Z

Orientation	Field	Result (Pass/Fail)	Remark - :

^{**}Note: Not applicable, because no any component can be influenced by power magnetic fields.

Performance & Result:

Criteria A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
Criteria B:	The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
Criteria C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.

**Observation: N/A

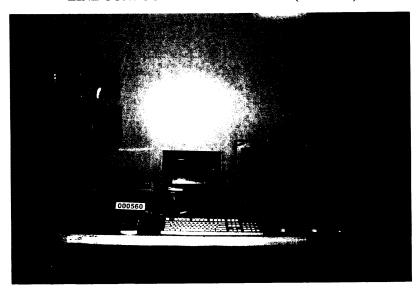
Accredited Lab. of NEMKO, A2LA, BSMI Listed Lab. of FCC, VCCI, MOC

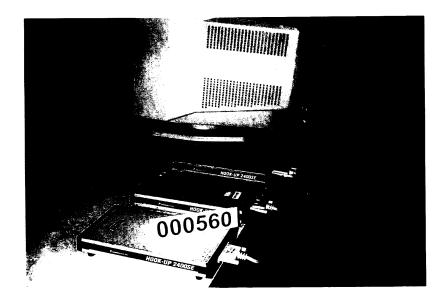
A2LA Certificate #: 824.01 (for Emission) NEMKO Authorization #: ELA 124 (for EMC)

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LINE CONDUCTED EMISSION TEST (EN 55022)



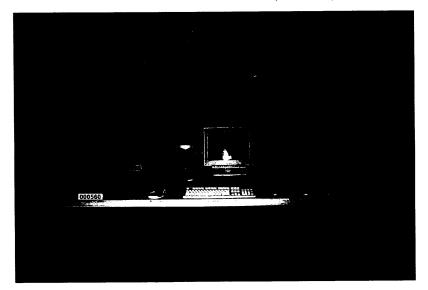


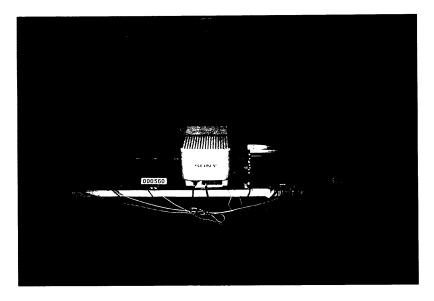
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RADIATED EMISSION TEST (EN 55022)



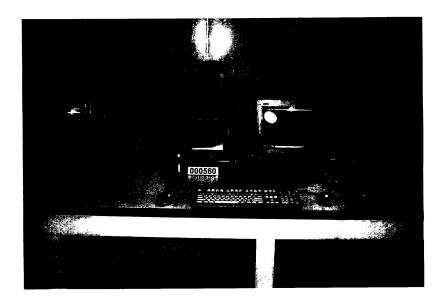


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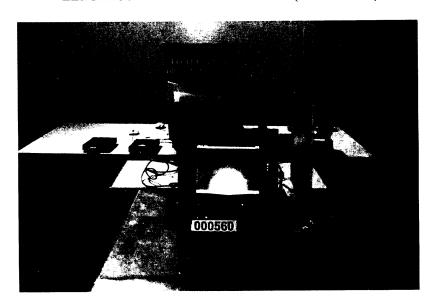


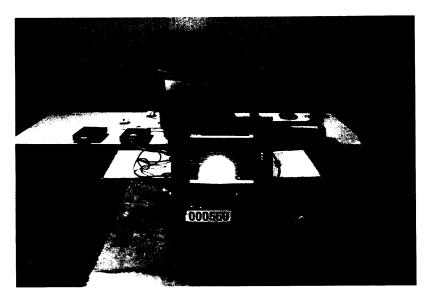
POWER HARMONIC & VOLTAGE FLUCTUATION / FLICKER TEST (EN 61000-3-2, EN 61000-3-3)





ELECTROSTATIC DISCHARGE TEST (EN 61000-4-2)



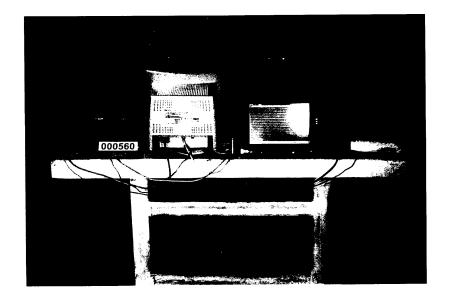


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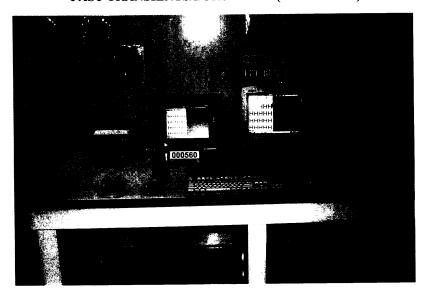


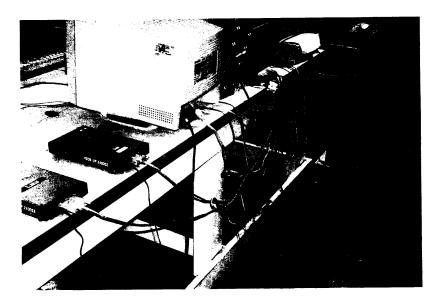
RADIATED ELECTROMAGNETIC FIELD (ENV 50140 & ENV 50204)





FAST TRANSIENTS/BURST TEST (EN 61000-4-4)



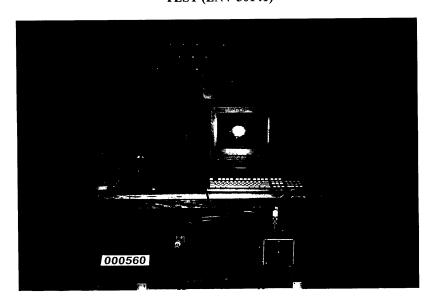


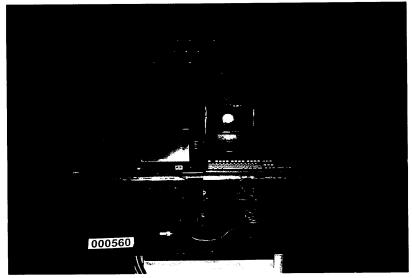
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CONDUCTED DISTURBANCE, INDUCED BY RADIO-FREQUENCY FIELDS TEST (ENV 50141)



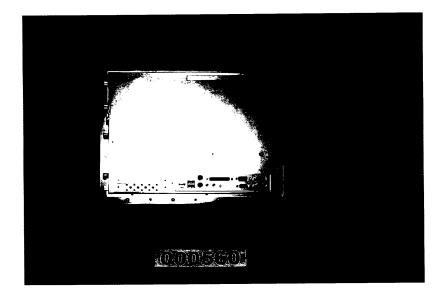


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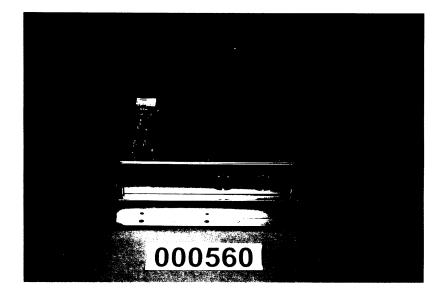
A2LA Certificate #: 824.01 (for Emission) NEMKO Authorization #: ELA 124 (for EMC) Page 56

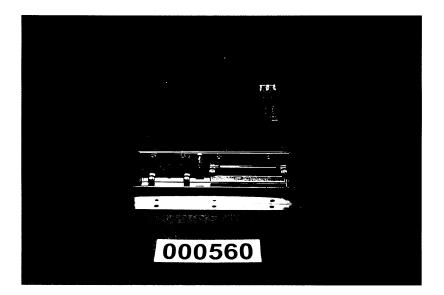
Report Number: 000560-E August 16, 2000



APPENDIX 2

PHOTOGRAPHS OF EUT





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